

# DMD-based Compressive Imaging & Spectroscopy

## *A 1-Pixel Camera & Beyond*

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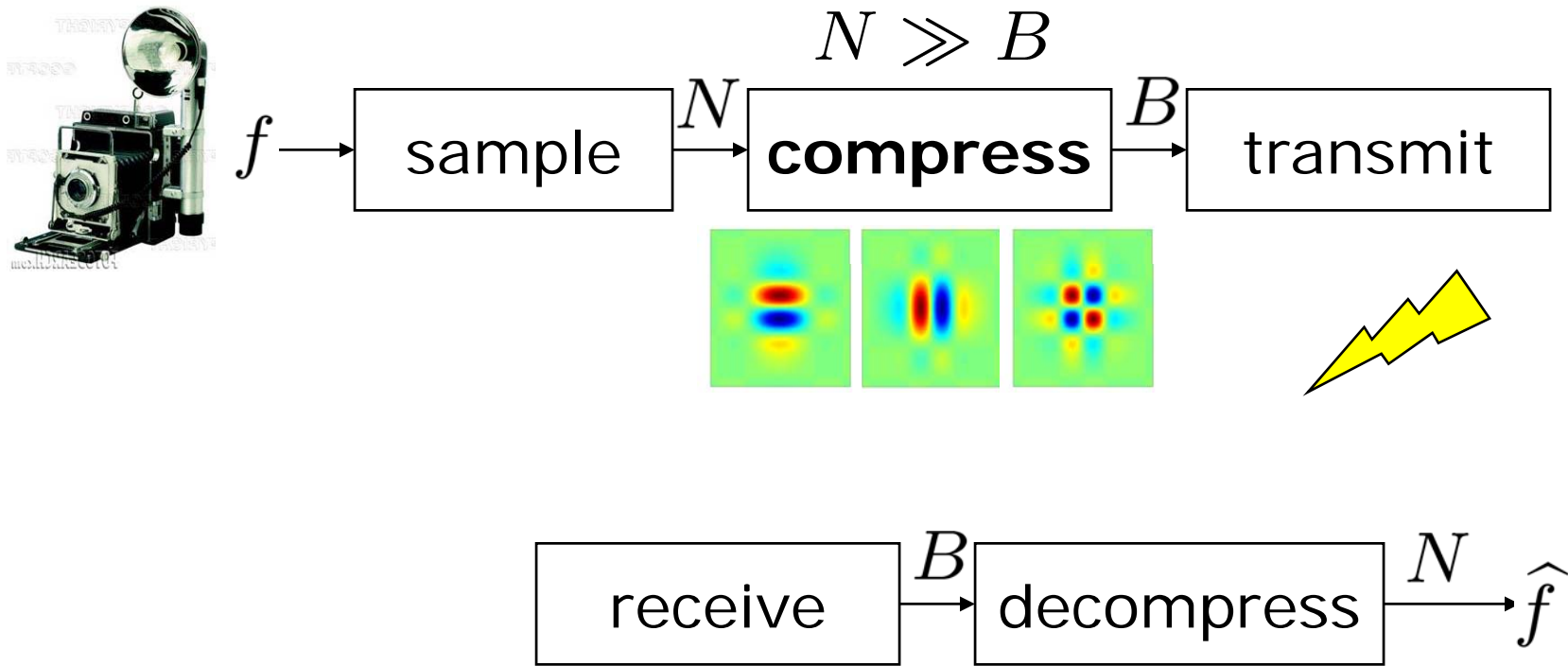


# New Acquisition Hardware

- CS changes the rules of the data acquisition game
  - exploits a priori signal/image *sparsity* information
- Same random projections / hardware can be used for *any* compressible signal class (*generic*)
- Simplifies hardware and algorithm design
- Random projections automatically *“encrypted”*
- Very simple encoding
- Robust to measurement loss and quantization
- Asymmetrical processing (most at decoder)

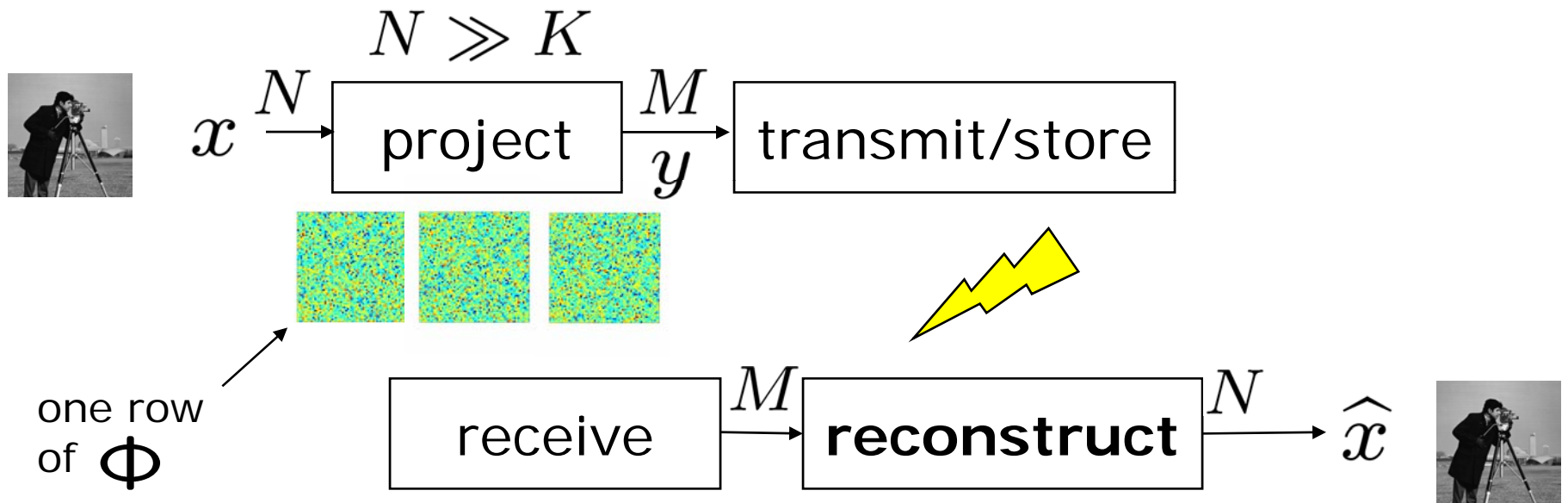
# Conventional Sensing

- The typical sensing/compression setup
  - compress = transform, sort coefficients, encode
  - most computation at *sensor* (asymmetrical)



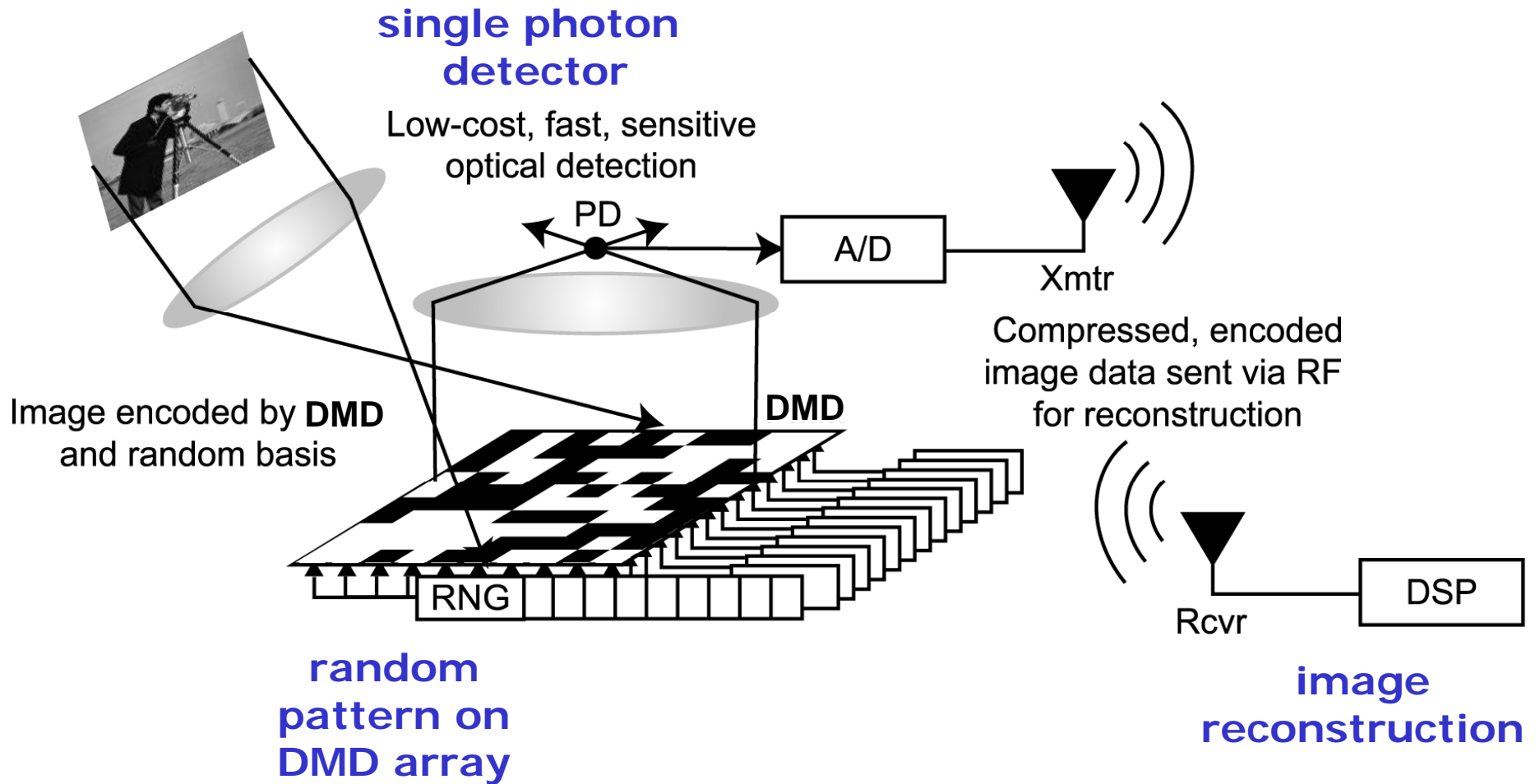
# Compressive Sensing

- Measure linear projections onto *random* basis where data is *not sparse/compressible*

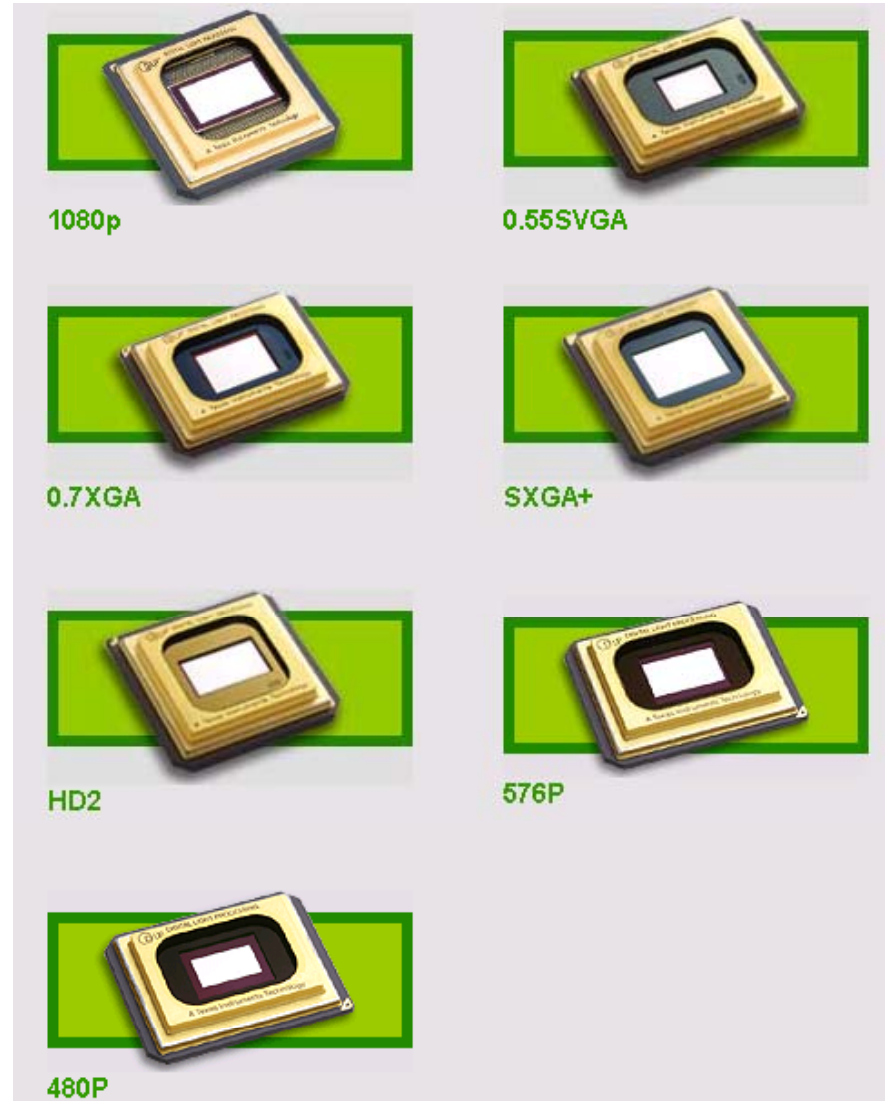
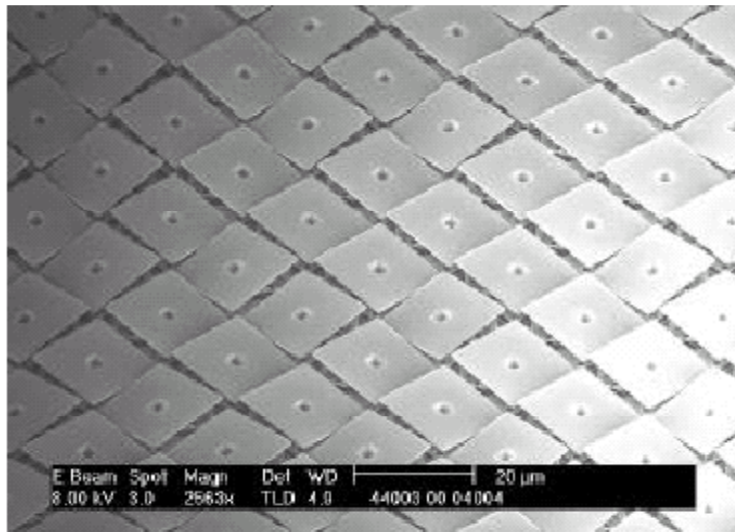
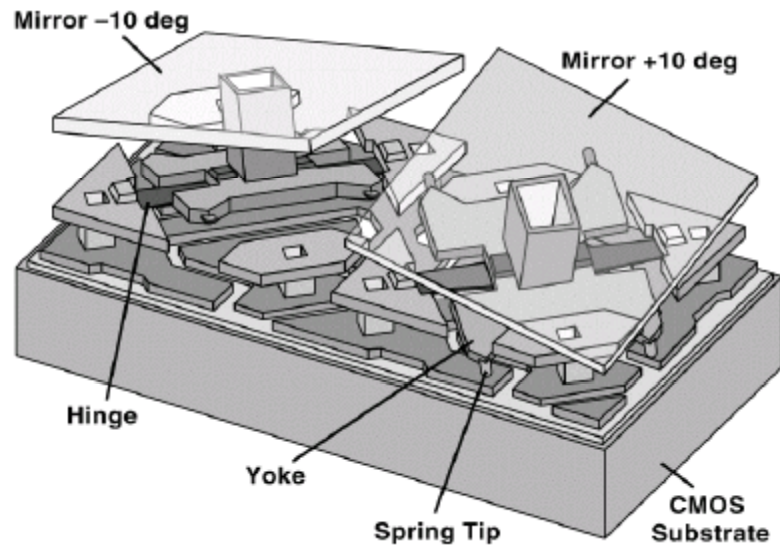


- Reconstruct via *nonlinear processing* (optimization)

# Rice 1-Pixel Camera



# TI Digital Micromirror Device (DMD)

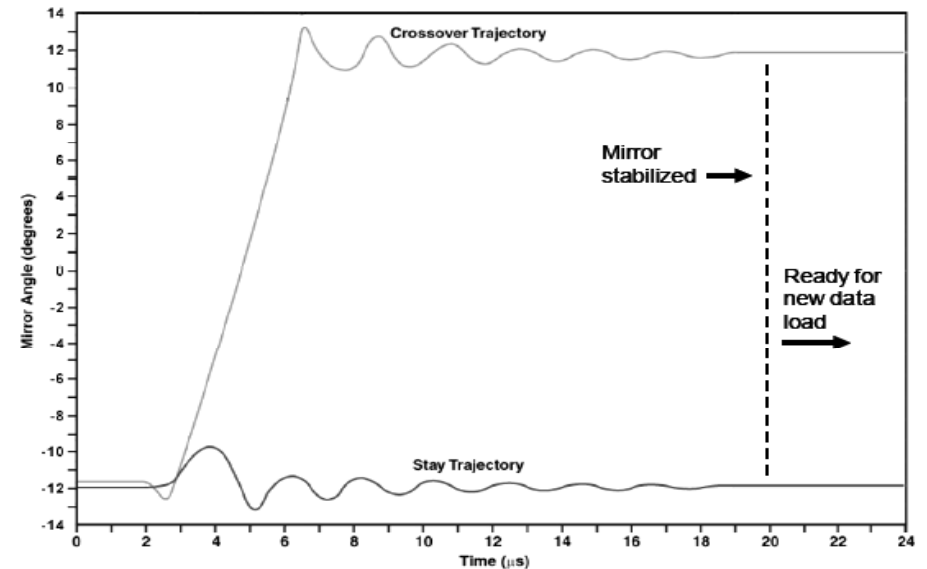


DLP 1080p --> 1920 x 1080 resolution

# (Pseudo) Random Optical Projections

- Binary patterns are loaded into mirror array:

- light reflected towards the lens/photodiode (1)
- light reflected elsewhere (0)
- pixel-wise products summed by lens



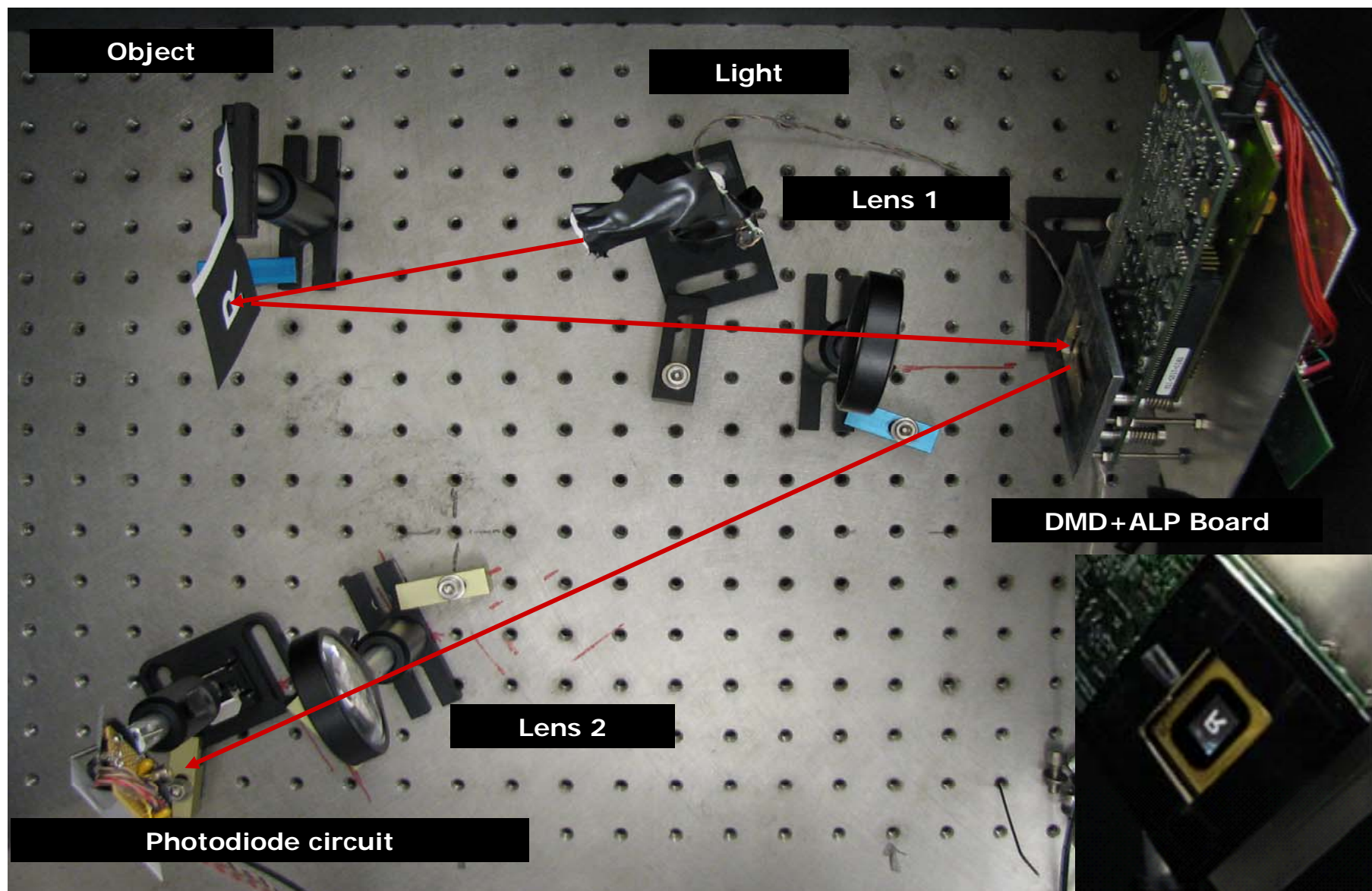
- Pseudorandom number generator outputs measurement basis vectors

...





# Rice CI Camera

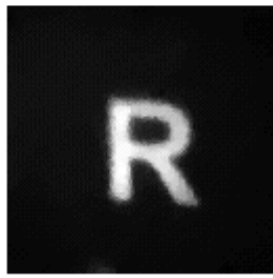




# Image Acquisition



Original



16384 Pixels  
1600 Measurements  
(10%)



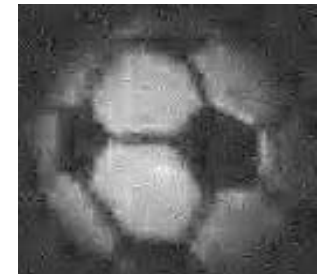
16384 Pixels  
3300 Measurements  
(20%)



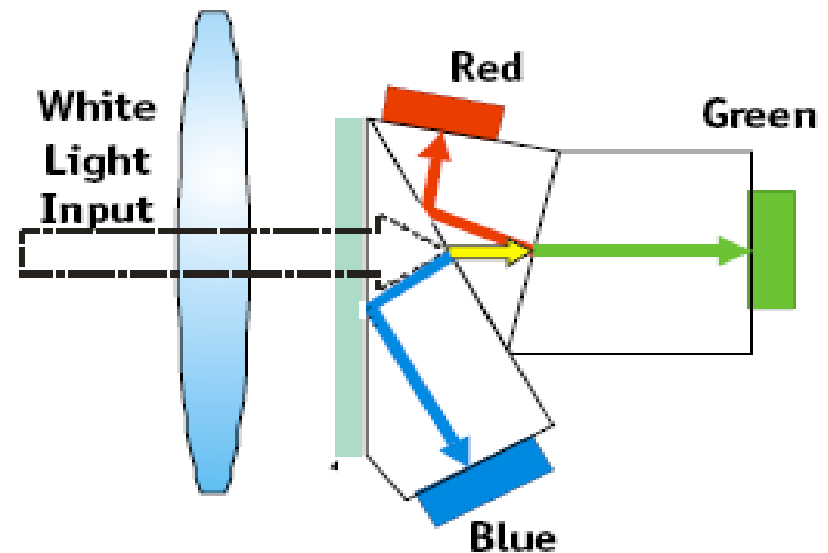
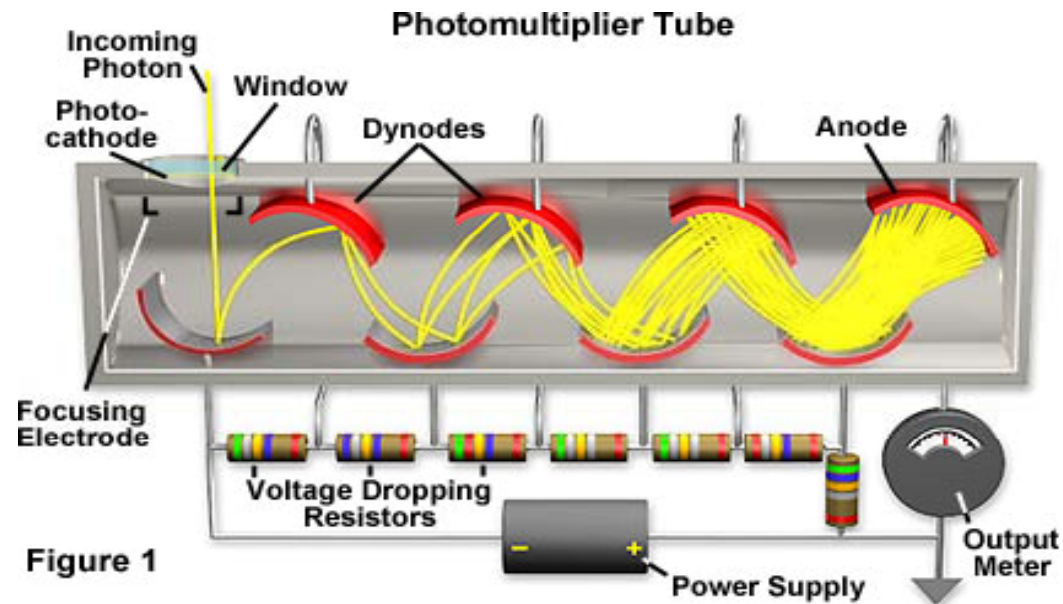
65536 Pixels  
1300 Measurements  
(2%)



65536 Pixels  
3300 Measurements  
(5%)

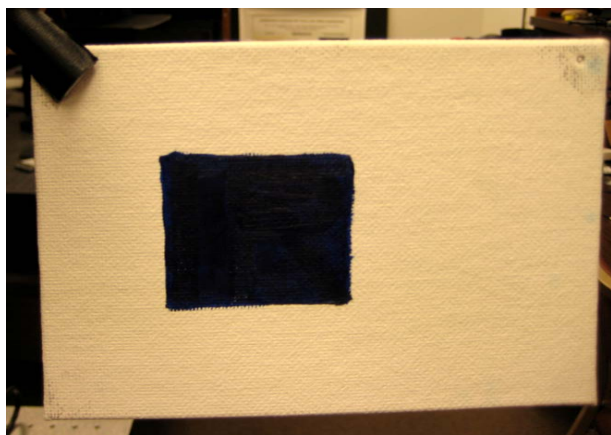
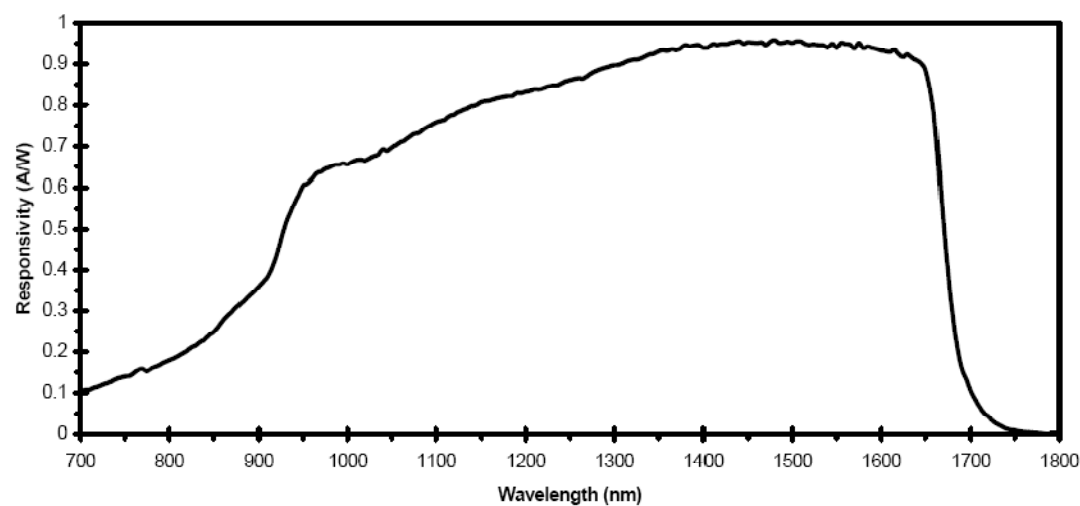


# CS Low-Light Imaging with PMT

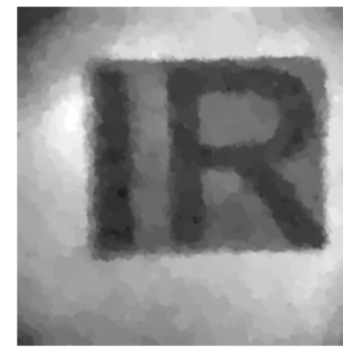


True color low-light imaging:  
256 x 256 image with 10:1 compression

# CS Imaging in the Infrared



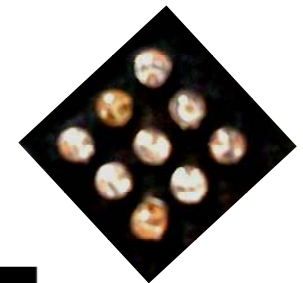
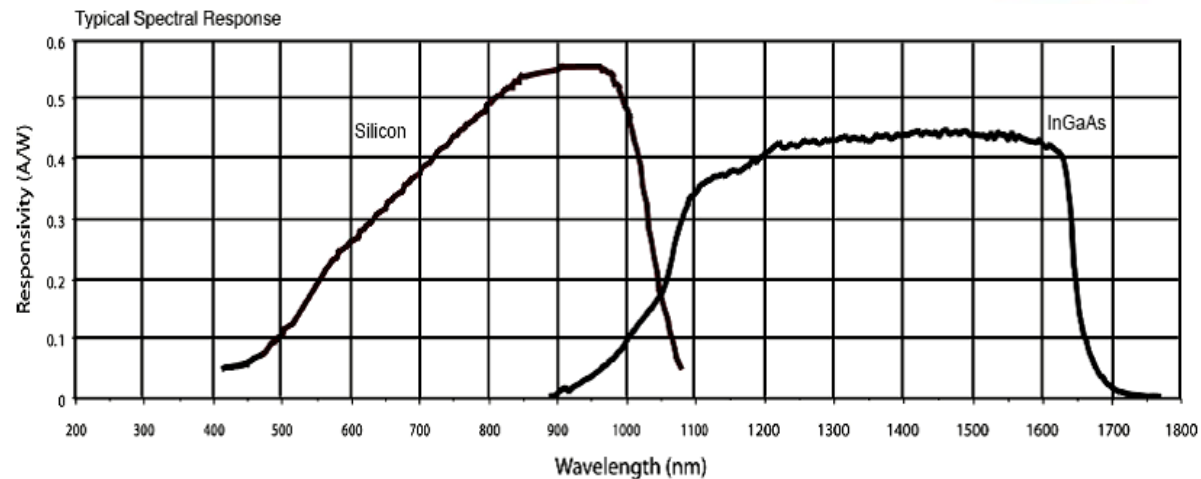
20%



5%

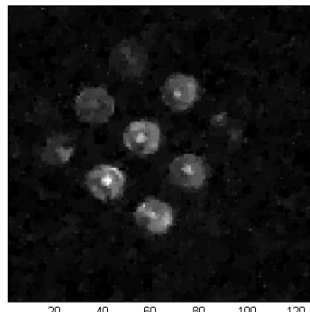
# Dual Visible/Infrared Imaging

Detector: commercial dual-band sandwich photodetector with a Si substrate mounted above an InGaAs substrate



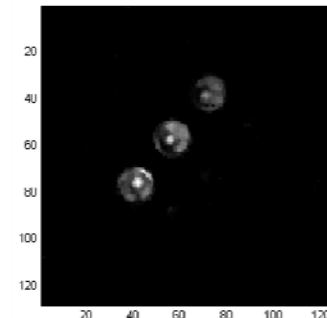
5%

Visible

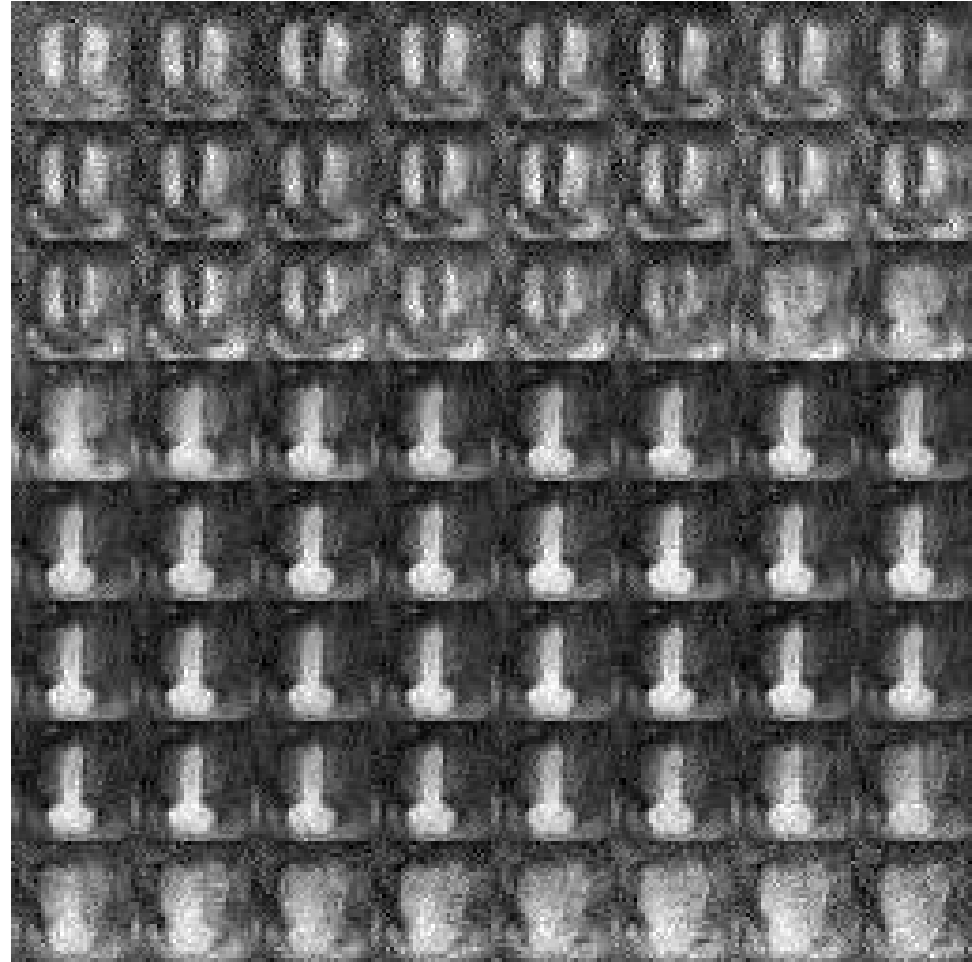
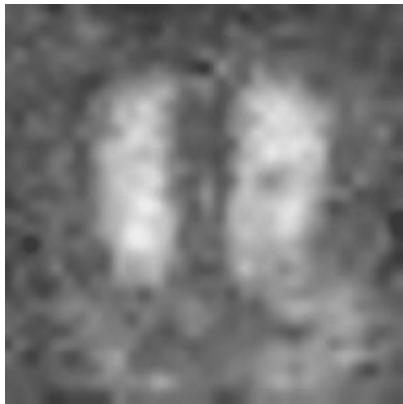
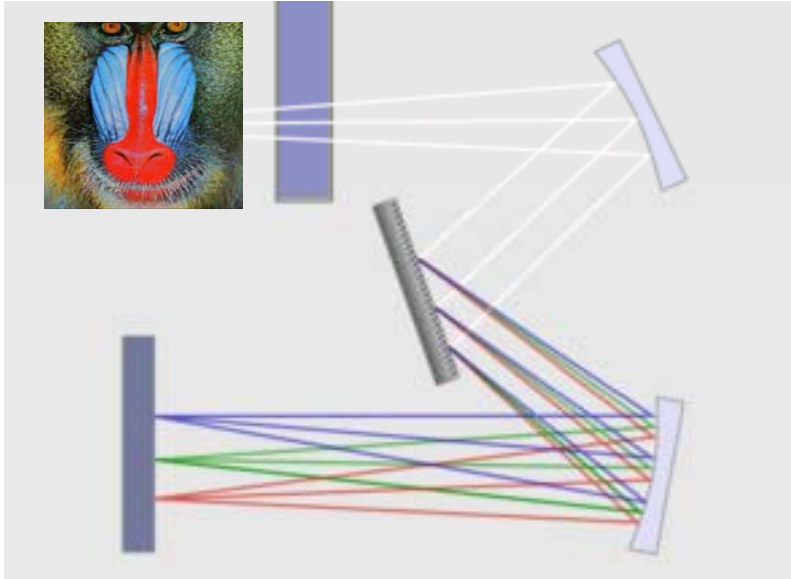


5%

Infrared

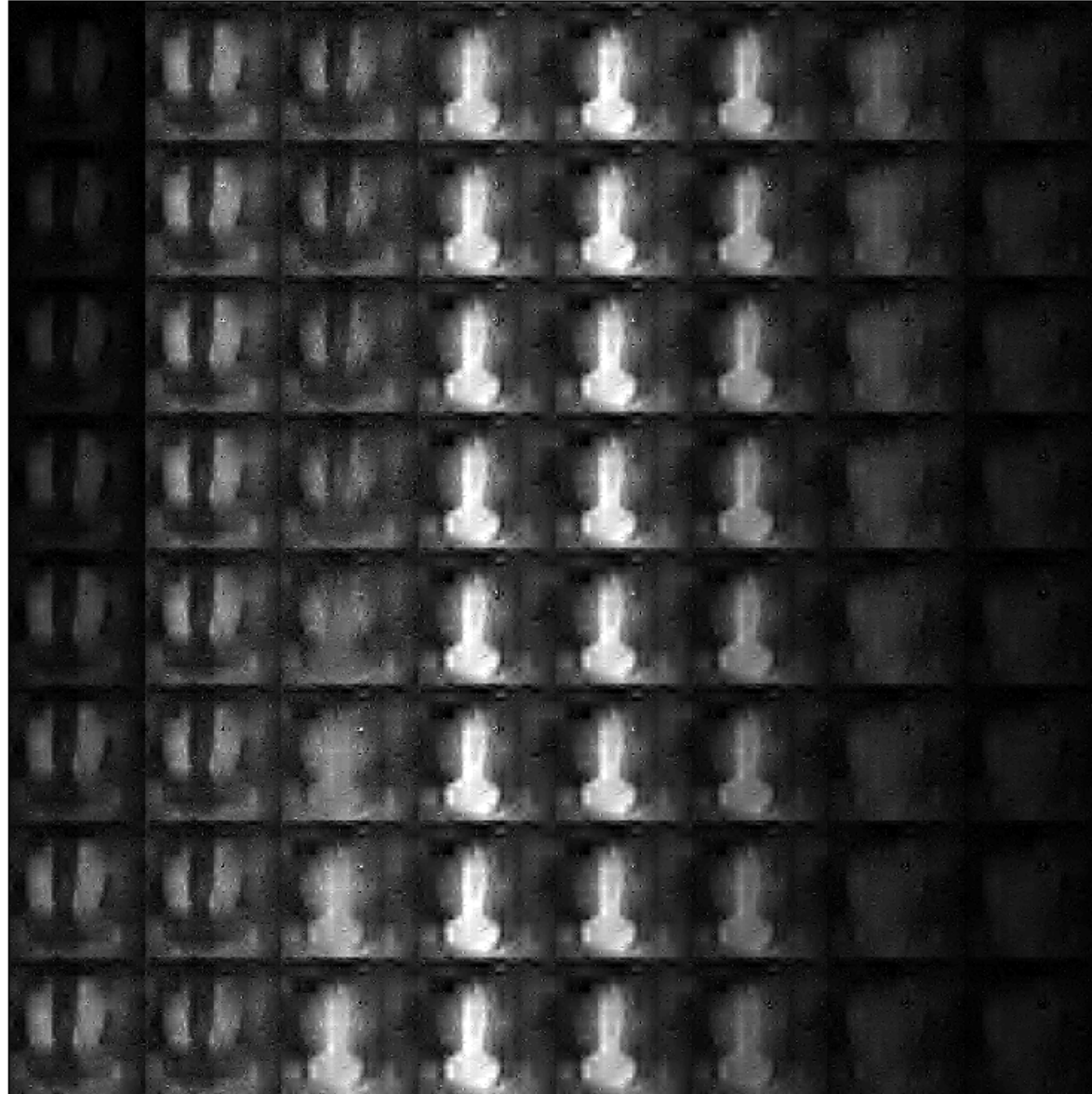


# Hyperspectral Mandrill 32x32x64



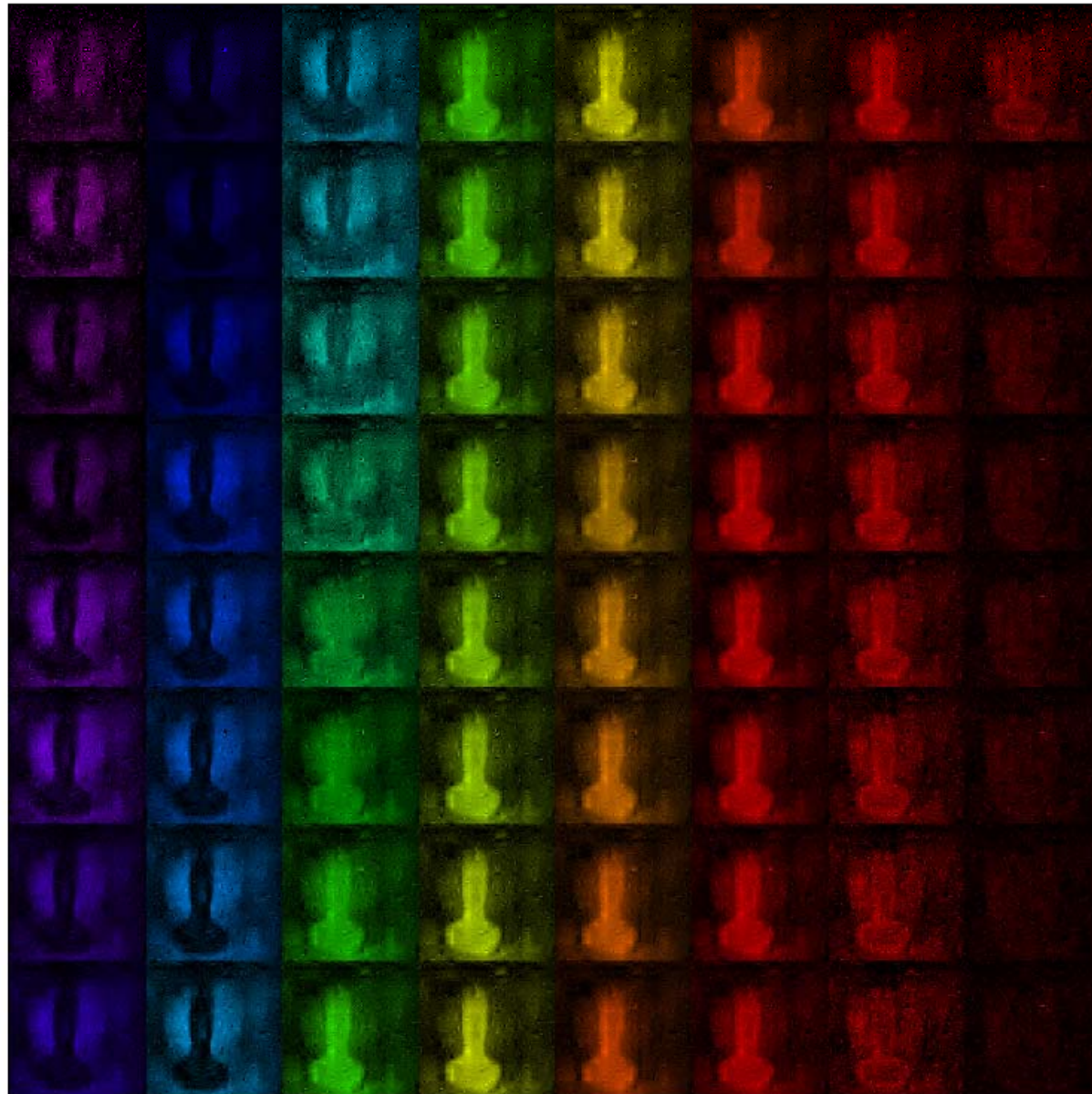


independent reconstruction of each band

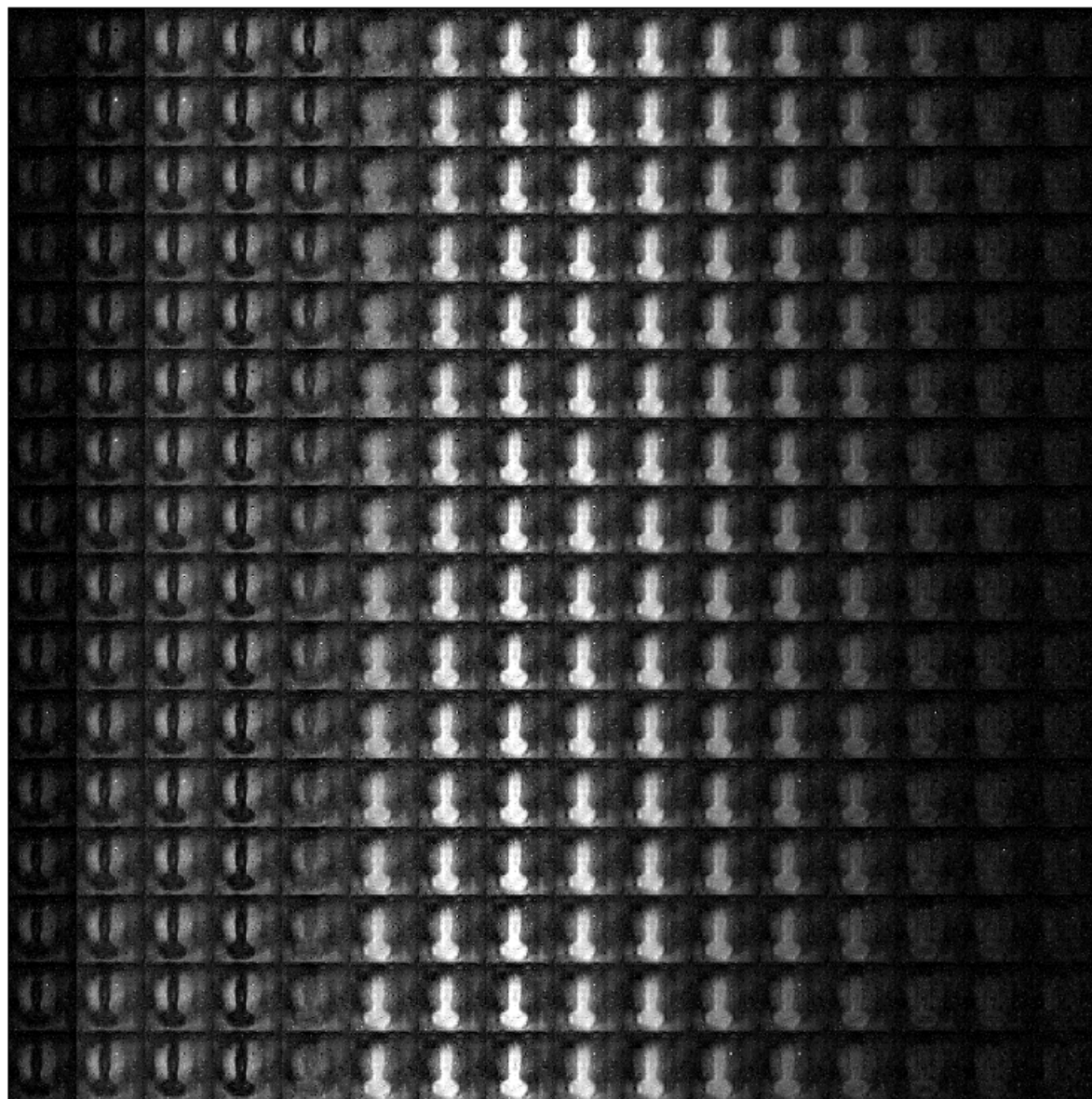




joint reconstruction with a spatial wavelet/spectral Fourier tensor product sparsity basis

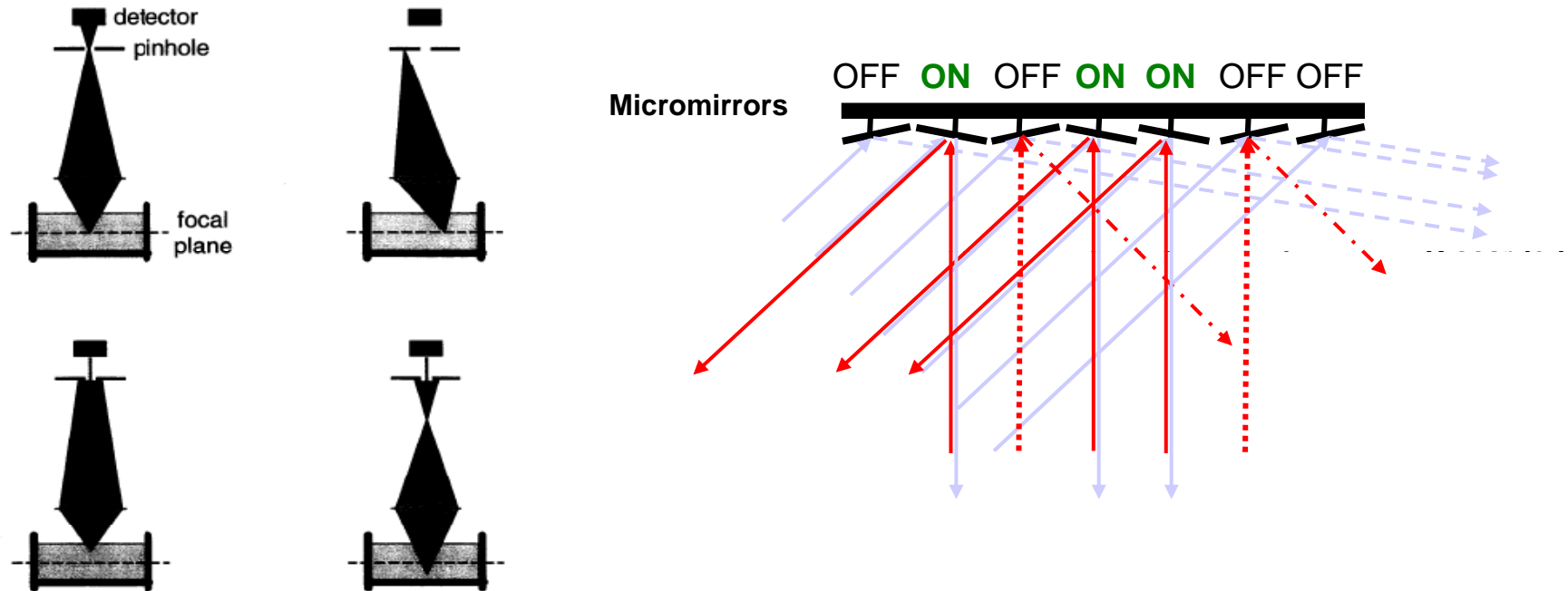


joint reconstruction with a spatial wavelet/spectral Fourier tensor product sparsity basis



# CS Confocal Microscopy

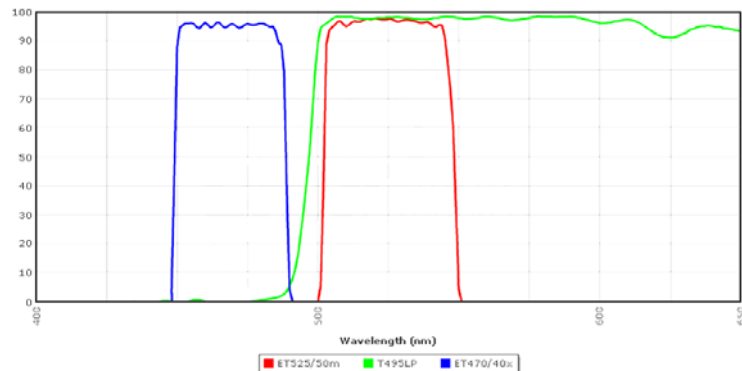
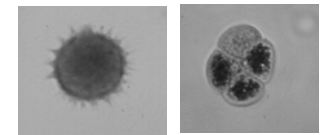
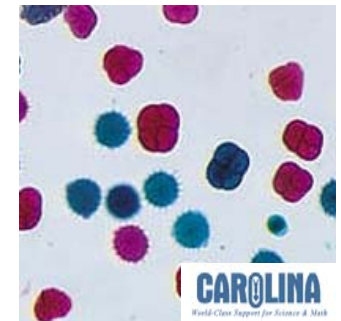
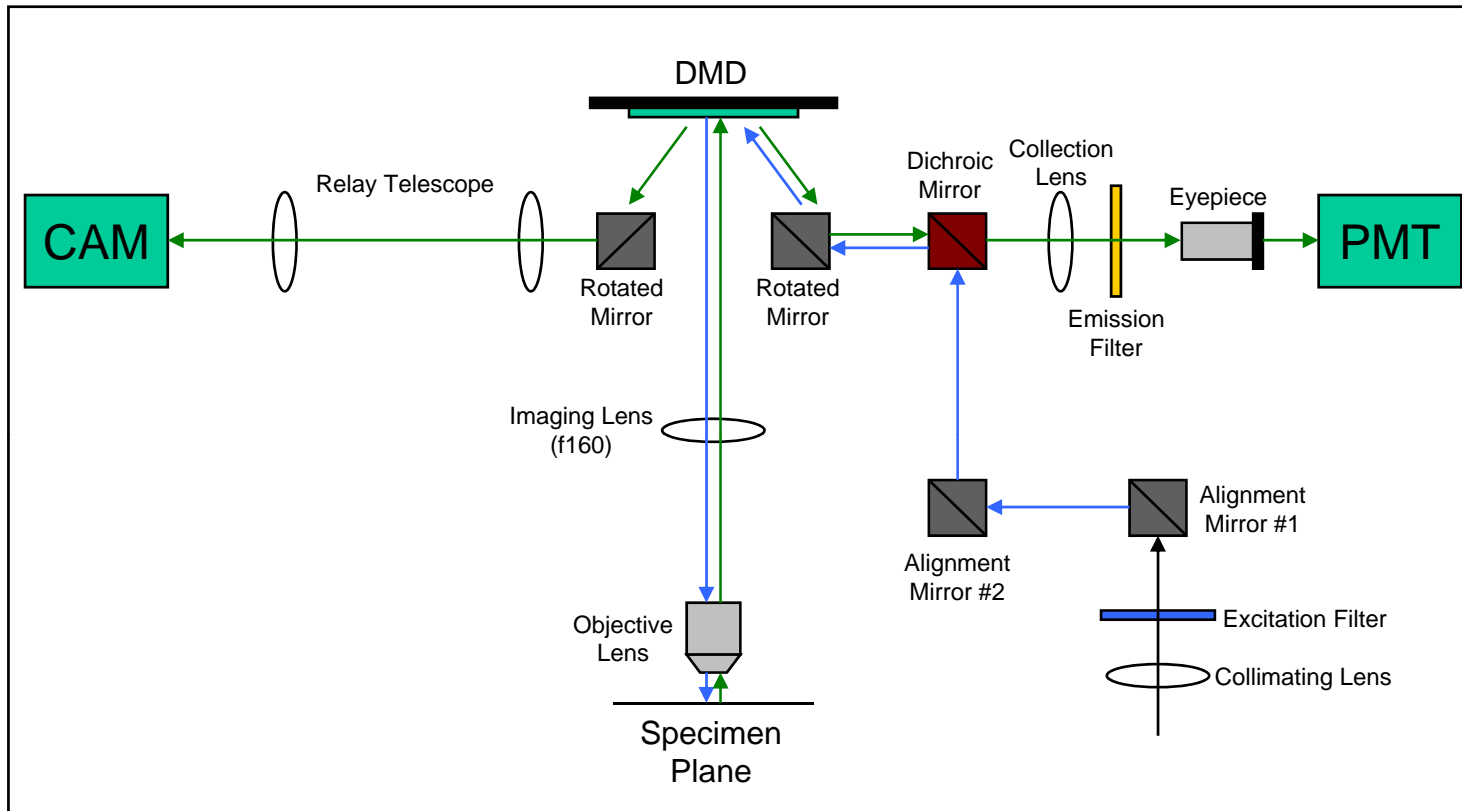
**An imaging technique used to increase contrast and/or to reconstruct 3-D images by using a pinhole to eliminate out-of-focus light**



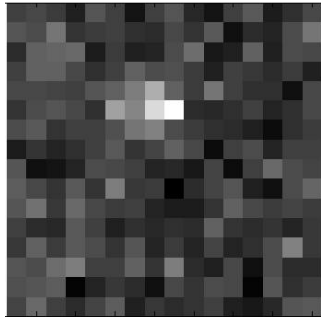
## Compressive Sensing vs. Traditional Raster Scan

- **50% of the illumination used in the CS measurement compared to less than 1% used in a raster measurement**
- **Additionally, CS will make far fewer measurements but will still obtain the same size final image**

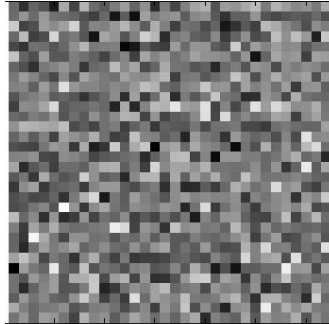
# DMD-based CS Microscope Layout



# CS Fluorescence Microscopy



**16 x 16 raster  
(Gain: 2e6)**

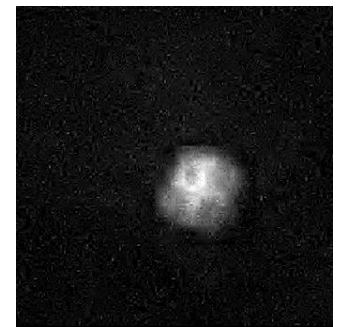


**32 x 32 raster**



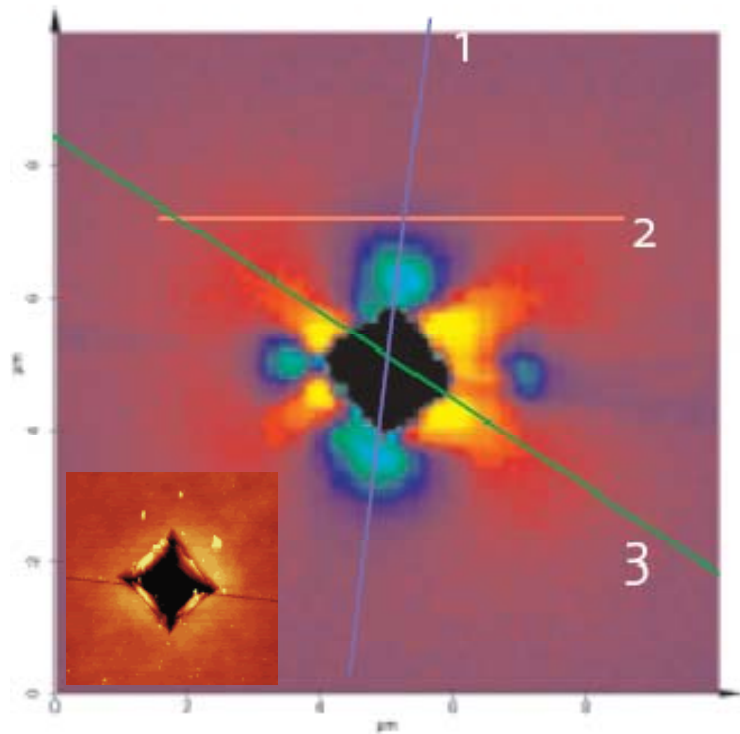
**128 x 128 CS  
1600 measurements  
(Gain: 6e5)**

- Using the raster scan, the signal quickly drops below our detection limit.
- Compressive sensing we can obtain a high resolution even with decreased detector gain and without the threat of photobleaching.





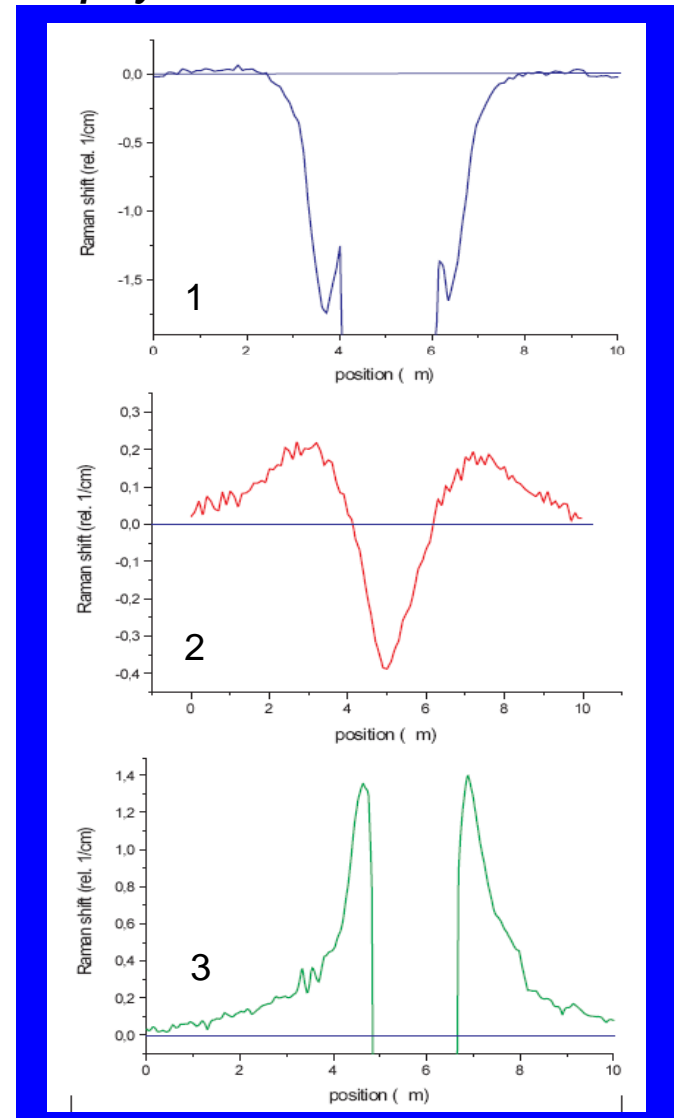
# Confocal Measurement of Stress in Silicon



**Confocal Raman image of a Vickers indent into silicon (10 x 10 μm). The image was calculated by determining the peak position of the Si-Raman line of each measured spectrum. Inset is the corresponding AFM image. (Data courtesy of Witec Instruments GmbH.)**

U. Schmidt et al., *Vibrational Spectroscopy* **42**, 93 (2006).

**Three cross-sections are marked in the stress image on the left and displayed below.**

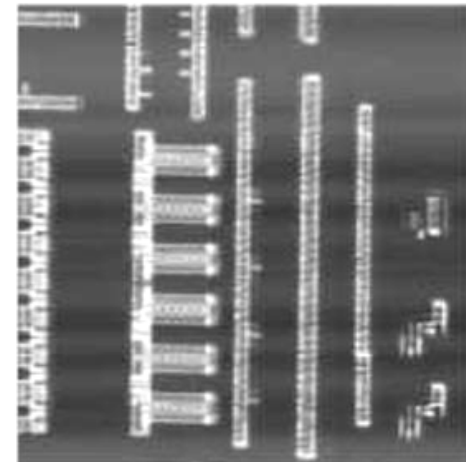
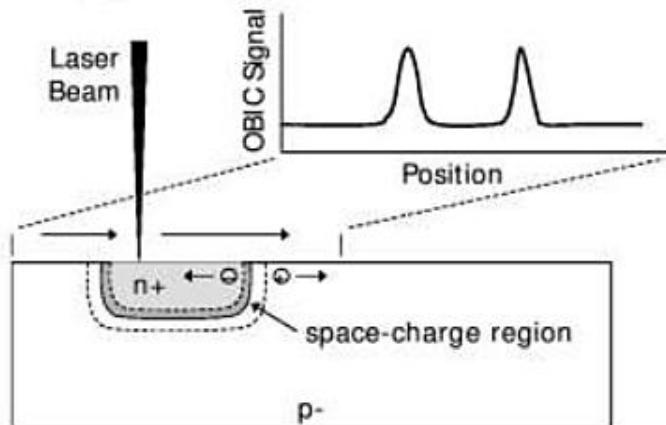




# Optical Beam Induced Current Imaging

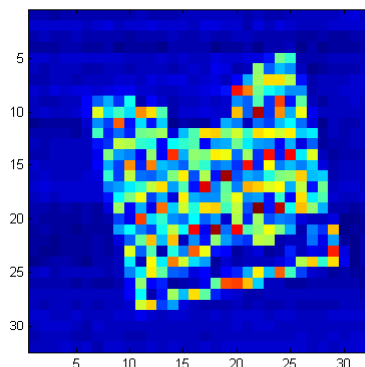
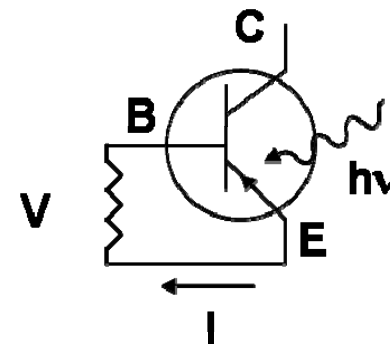
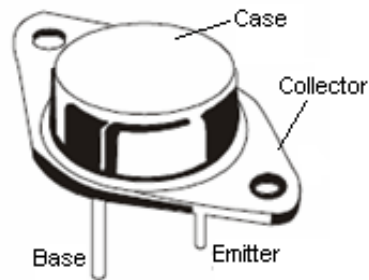
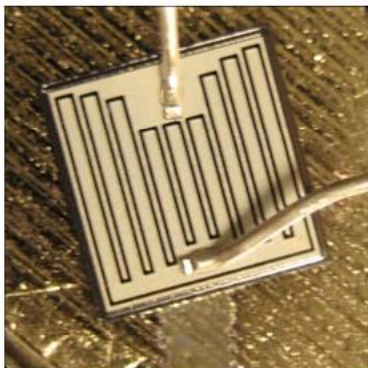
## 1. OBIC Theory

- **failure analysis** to locate electrically active defects such as diffusion, stacking faults, latch-up and leakage in integrated circuits (IC)
- monitor the **nonrandom recombination** current of the electron-hole pairs generated by a laser as it is **scanned** across the chip surface.
- variations in **currents** are converted into variations in **contrast** to form the OBIC image

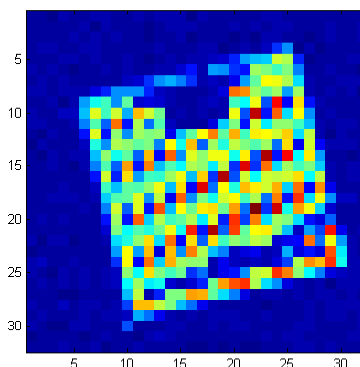


# Optical Beam Induced Current Imaging

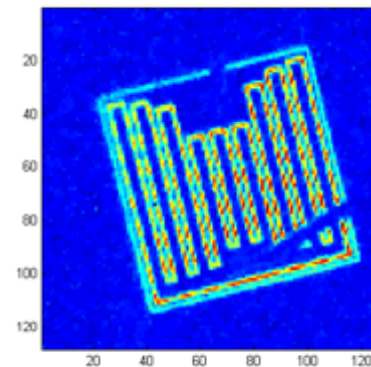
**Target: NTE68 (PNP) is a complementary silicon power transistor designed for high power audio, disk head positioners**



32 x 32 Raster

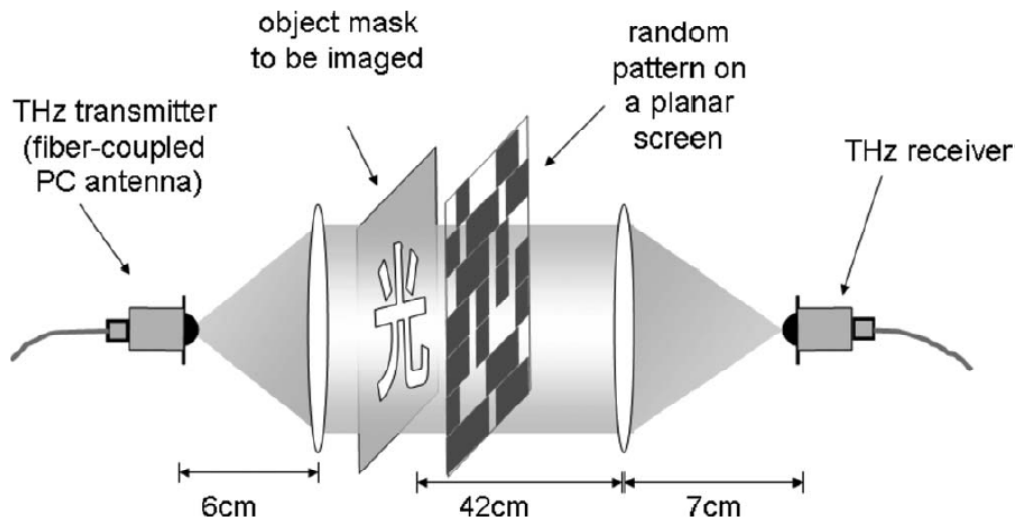


32 x 32 CS

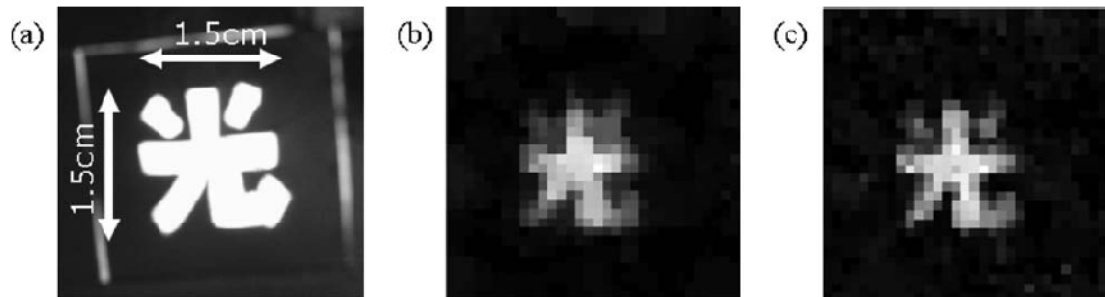


128 x 128 CS

# CS THz Camera



32 x 32 PCB masks

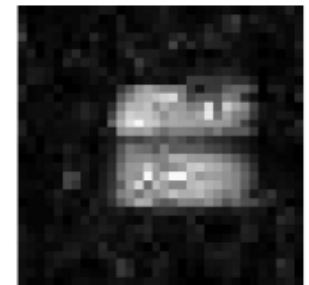


Object mask

CS recon  
300 measurements

CS recon  
600 measurements

THz  
Amplitude



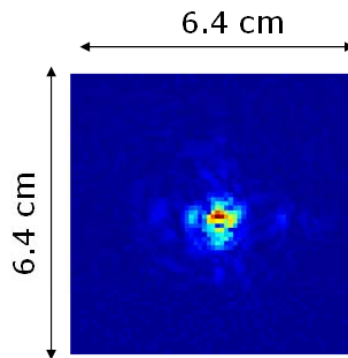
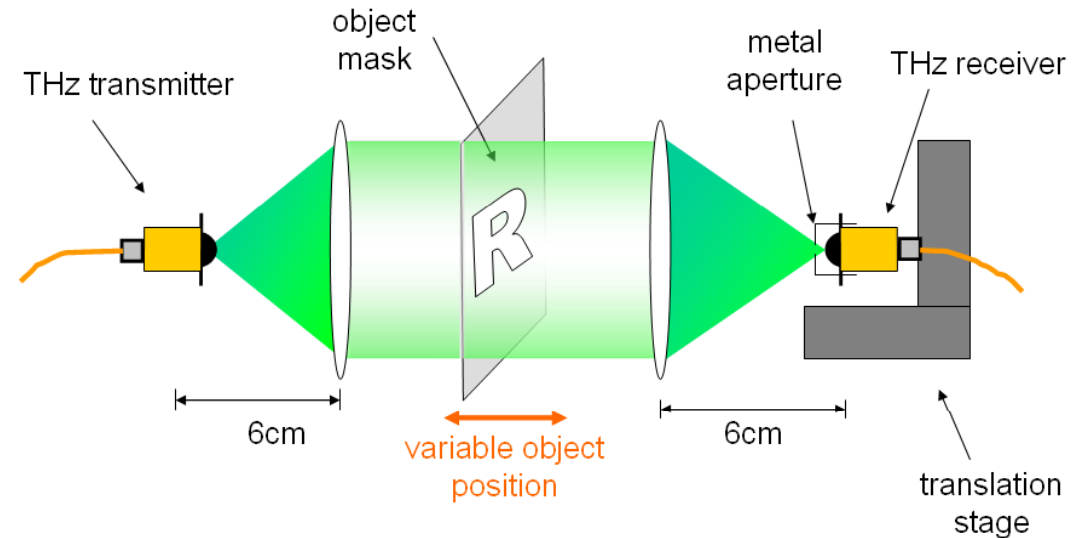
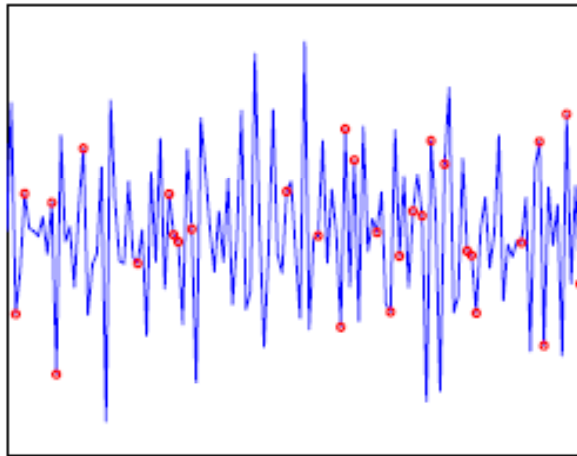
THz Phase



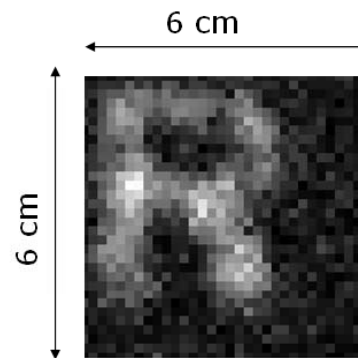
*Mittleman Group, Rice University*

APPLIED PHYSICS LETTERS 93, 121105 (2008)

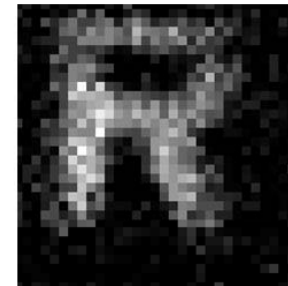
# THz Camera 2: Sampling in Fourier



Fourier Transform  
of object  
(Magnitude-only)



CPR Reconstruction  
(4096 measurements)



CSPR Reconstruction  
(1000 measurements)

# Conclusions

- Compressive imaging
  - a new imaging framework based on compressive sensing
  - exploit a priori image sparsity information
  - based on new uncertainty principles
- Proof of concept: CS camera
  - single sensor element
  - universal, simple, robust image coding
  - imaging beyond the visible
  - hyperspectral
  - confocal microscopy



[dsp.rice.edu/cs/camera](http://dsp.rice.edu/cs/camera)